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**Valvodni tip dielektričnih resonatorjev – 1-4. del: Splošni podatki in pogoji preskušanja – Metode za meritve kompleksne relativne permitivnosti dielektričnih resonatorskih materialov pri frekvencah z milimetrsko valovno dolžino (IEC 61338-1-4:2005)**

Waveguide type dielectric resonators - Part 1-4: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at millimetre-wave frequency (IEC 61338-1-4:2005)

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**Waveguide type dielectric resonators  
Part 1-4: General information and test conditions -  
Measurement method of complex relative permittivity  
for dielectric resonator materials at millimetre-wave frequency  
(IEC 61338-1-4:2005)**

Résonateurs diélectriques  
à modes guidés  
Partie 1-4: Informations générales  
et conditions d'essais -  
Méthode de mesure de la permittivité  
relative complexe des matériaux  
des résonateurs diélectriques fonctionnant  
à des fréquences millimétriques  
(CEI 61338-1-4:2005)

Dielektrische Resonatoren  
vom Wellenleitertyp  
Teil 1-4: Allgemeine Informationen  
und Prüfbedingungen -  
Messverfahren für die komplexe relative  
Dielektrizitätskonstante von dielektrischen  
Resonatorwerkstoffen im Mikrowellen-  
Frequenzbereich  
(IEC 61338-1-4:2005)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: rue de Stassart 35, B - 1050 Brussels**

## Foreword

The text of document 49/748/FDIS, future edition 1 of IEC 61338-1-4, prepared by IEC TC 49, Piezoelectric and dielectric devices for frequency control and selection, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61338-1-4 on 2005-12-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2006-09-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2008-12-01

This European Standard makes reference to International Standards. Where the International Standard referred to has been endorsed as a European Standard or a home-grown European Standard exists, this European Standard shall be applied instead. Pertinent information can be found on the CENELEC web site.

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## Endorsement notice

The text of the International Standard IEC 61338-1-4:2005 was approved by CENELEC as a European Standard without any modification.

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# INTERNATIONAL STANDARD

# IEC 61338-1-4

First edition  
2005-11

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## Waveguide type dielectric resonators –

### Part 1-4:

### General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at millimetre-wave frequency

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**WAVEGUIDE TYPE DIELECTRIC RESONATORS –**

**Part 1-4: General information and test conditions –  
Measurement method of complex relative permittivity for  
dielectric resonator materials at millimetre-wave frequency**

FOREWORD

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International Standard IEC 61338-1-4 has been prepared by IEC Technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/748/FDIS	49/751/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.



IEC 61338 consists of the following parts, under the general title *Waveguide type dielectric resonators*:

- Part 1: Generic specification
- Part 1-3: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at microwave frequency
- Part 1-4: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at millimetre-wave frequency
- Part 2: Guidelines for oscillator and filter applications
- Part 4: Sectional specification
- Part 4-1: Blank detail specification

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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A bilingual version of this publication may be issued at a later date.

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## WAVEGUIDE TYPE DIELECTRIC RESONATORS –

### Part 1-4: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at millimetre-wave frequency

#### 1 Scope and object

This part of IEC 61338 describes the measurement method of dielectric properties for dielectric resonator materials at millimetre-wave frequency.

This standard consists of two measurement methods: a) the dielectric rod resonator method excited by NRD-guide (Non-Radiative Dielectric waveguide) and b) the cut-off waveguide method excited by coaxial cables with small loops.

- a) The dielectric rod resonator method excited by NRD-guide is similar to the dielectric rod resonator method given in IEC 61338-1-3. This method has the following characteristics:
- a complete and exact mathematical solution of complex permittivity is given by computer software;
  - the measurement error is less than 0,3 % for  $\varepsilon'$  and less than  $0,05 \times 10^{-4}$  for  $\tan \delta$ ;
  - the applicable measuring ranges of complex permittivity for this method are as follows:  
frequency:  $30 \text{ GHz} < f < 100 \text{ GHz}$ ;
- relative permittivity:  $2 < \varepsilon' < 30$ ;  
loss factor:  $10^{-6} < \tan \delta < 10^{-2}$ .
- b) The cut-off waveguide method excited by coaxial cables with small loops uses a dielectric plate sample placed in a circular cylinder of the  $TE_{011}$  mode. This method has the following characteristics:
- fringe effect is corrected using the correction charts on the basis of rigorous analysis;
  - the measurement error is less than 0,5 % for  $\varepsilon'$  and less than  $0,05 \times 10^{-4}$  for  $\tan \delta$ ;
  - the  $TCF$  is measured with high accuracy;
  - the applicable measuring ranges of dielectric properties for this method are as follows:  
frequency:  $30 \text{ GHz} < f < 100 \text{ GHz}$ ;
- relative permittivity:  $2 < \varepsilon' < 30$ ;  
loss factor:  $10^{-6} < \tan \delta < 10^{-2}$ .

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61338-1-3, *Waveguide type dielectric resonators – Part 1-3: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at microwave frequency*

### 3 Measurement parameter

The measuring parameters are defined as follows:

$$\dot{\varepsilon}_r = \varepsilon' - j\varepsilon'' = D/(\varepsilon_0 E) \quad (1)$$

$$\tan \delta = \varepsilon'' / \varepsilon' \quad (2)$$

$$TC\varepsilon = \frac{1}{\varepsilon_{\text{ref}}} \frac{\varepsilon_T - \varepsilon_{\text{ref}}}{T - T_{\text{ref}}} \times 10^6 \quad (1 \times 10^{-6}/\text{K}) \quad (3)$$

$$TCF = \frac{1}{f_{\text{ref}}} \frac{f_T - f_{\text{ref}}}{T - T_{\text{ref}}} \times 10^6 \quad (1 \times 10^{-6}/\text{K}) \quad (4)$$

where

$D$  is the electric flux density;

$E$  is the electric field strength;

$\varepsilon_0$  is the permittivity in a vacuum;

$\dot{\varepsilon}_r$  is the complex relative permittivity;

$\varepsilon'$  and  $\varepsilon''$  are the real and imaginary components of the complex relative permittivity  $\dot{\varepsilon}_r$ ;

$TC\varepsilon$  is the temperature coefficient of relative permittivity, and  $TCF$  being the temperature coefficient of resonance frequency;

$\varepsilon_T$  and  $\varepsilon_{\text{ref}}$  are the real parts of the complex relative permittivity at temperature  $T$  and reference temperature  $T_{\text{ref}}$  ( $T_{\text{ref}} = 20 \text{ }^\circ\text{C}$  to  $25 \text{ }^\circ\text{C}$ ), respectively;

$f_T$  and  $f_{\text{ref}}$  are the resonance frequency at temperature  $T$  and  $T_{\text{ref}}$ , respectively.

The  $TCF$  is related to  $TC\varepsilon$  by the following equation:

$$TCF = -\frac{1}{2}TC\varepsilon - \alpha \quad (5)$$

where  $\alpha$  is the coefficient of thermal expansion of the dielectric specimen.

It should be noted that this equation is satisfied when the 100 % of electro-magnetic energy in the measuring resonance mode is concentrated inside the dielectric specimen. In the actual case,  $TCF$  deviates by several  $10^{-6}/\text{K}$  from the calculated value, because some portion of electro-magnetic energy is stored outside the dielectric specimen.

#### 4 Dielectric rod resonator method excited by NRD-guide

##### 4.1 Measurement equipment and apparatus

The measurement equipment and apparatus are as follows:

###### a) Measurement equipment

Figure 1 shows a schematic diagram of the equipment required for millimetre wave measurement. For the measurement of dielectric properties, only the information on the amplitude of transmitted power is needed, that is, the information on the phase of the transmitted power is not required. A scalar network analyzer can be used for the measurement, but a vector network analyzer has an advantage in precision of the measurement data.

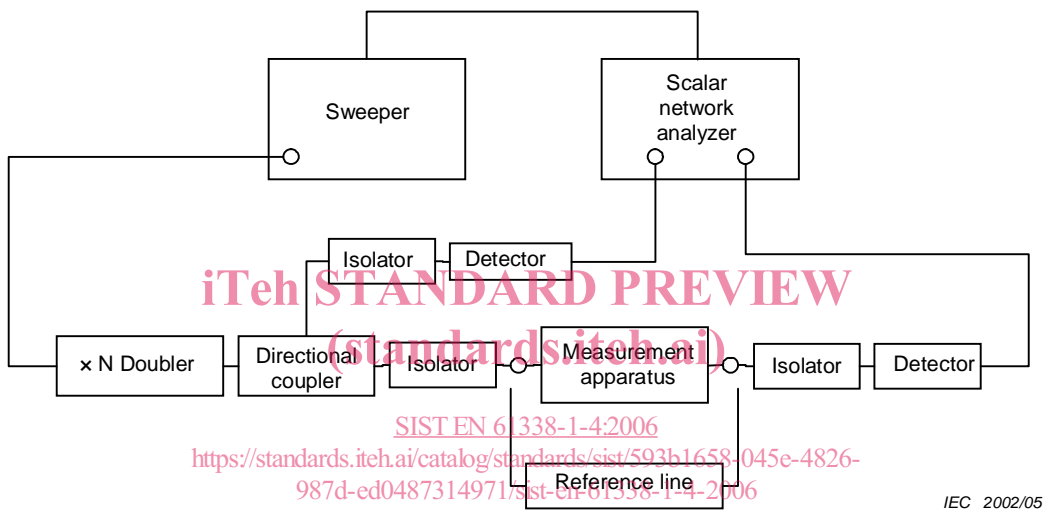


Figure 1a – Scalar network analyzer

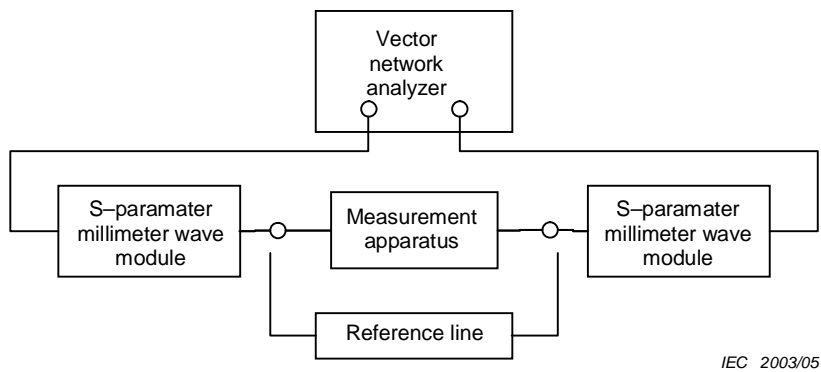


Figure 1b – Vector network analyzer

Figure 1 – Schematic diagram of measurement equipment